

NDS9958

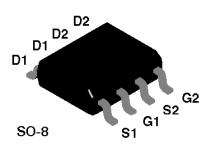
Dual N & P-Channel Enhancement Mode Field Effect Transistor

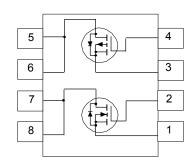
General Description

These dual N- and P-Channel enhancement mode power field \blacksquare N-Channel 3.5A, 20V, $R_{DS(ON)} = 0.1\Omega$ @ $V_{GS} = 10V$. effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as notebook computer power management, Half bridge motor control, cellular phone, and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- P-Channel -3.5A , -20V, $\rm R_{\rm DS(ON)}$ = 0.1 Ω @ $\rm V_{\rm GS}$ = -10V.
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.
- Dual (N & P-Channel) MOSFET in surface mount package.





Absolute Maximum Ratings T_x = 25°C unless otherwise noted

Symbol	Parameter		N-Channel	P-Channel	Units	
V _{DSS}	Drain-Source Voltage		20	-20	V	
/ _{GSS}	Gate-Source Voltage		± 20	± 20	V	
D	Drain Current - Continuous T _A = 25°C	(Note 1a)	± 3.5	± 3.5	Α	
	- Continuous T _A = 70°C	(Note 1a)	± 2.8	± 2.8		
	- Pulsed T _A = 25°C		± 14	± 14		
) D	Power Dissipation for Dual Operation		2			
	Power Dissipation for Single Operation	(Note 1a)	1.6			
		(Note 1b)	1			
		(Note 1c)	0	9		
J,T _{STG}	Operating and Storage Temperature Range		-55 to	150	°C	
HERMA	L CHARACTERISTICS					
R _{OJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	7	8	°C/W	
R _{BJC}	Thermal Resistance, Junction-to-Case	(Note 1)	40			

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Symbol	Parameter	Conditions		Type	Min	Тур	Max	Units
OFF CHA	RACTERISTICS	·						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		N-Ch	20			V
		$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		P-Ch	P-Ch -20			
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V		N-Ch			1	μA
			T _J = 70°C				5	μA
		$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$		P-Ch			-1	μA
			T _J = 70°C				-5	μA
I _{GSSF}	Gate - Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V	•	All			100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V		All			-100	nA
ON CHAR	ACTERISTICS (Note 2)	•		•				
V _{GS(th)} Gate Threshold Voltage		$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	N-Ch	1	1.5	3	V	
,			T _J = 125°C		0.7	1.1	2.2	
		$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	1	P-Ch	-1	-2.2	-3	
			T _J = 125°C		-0.8	-1.9	-2.5	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_{D} = 3.5 \text{ A}$	'	N-Ch		0.062	0.1	Ω
			T _J = 125°C			0.085	0.14	
		$V_{GS} = -10 \text{ V}, I_D = -3.5 \text{ A}$	•	P-Ch		0.08	0.1	
			T _J = 125°C			0.11	0.16	
		$V_{GS} = 6V, I_D = 3.0 A$		N-Ch		0.073	0.12	
		$V_{GS} = -6 \text{ V}, I_{D} = -3.0 \text{ A}$		P-Ch		0.112	0.12	
		$V_{GS} = 4.5 \text{ V}, I_{D} = 1.0 \text{ A}$		N-Ch		0.08	0.15	
		$V_{GS} = -4.5 \text{ V}, I_{D} = -1.0 \text{ A}$		P-Ch		0.165	0.19	
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$		N-Ch	14			Α
		$V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$		P-Ch	-14			
		$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		N-Ch	3.5			
		$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$		P-Ch	-2.5			
g _{FS}	Forward Transconductance	$V_{DS} = 15 \text{ V}, I_{D} = 3.5 \text{ A}$		N-Ch		7		S
		$V_{DS} = -15 \text{ V}, I_{D} = -3.5 \text{ A}$		P-Ch		5		
DYNAMIC	CHARACTERISTICS	1						
C_{iss}	Input Capacitance	N-Channel		N-Ch		525		pF
		$V_{DS} = 10V, V_{GS} = 0 V,$ f = 1.0 MHz	P-Ch		785			
C_{oss}	Output Capacitance			N-Ch		315		pF
		P-Channel $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		P-Ch		500		
C _{rss}	Reverse Transfer Capacitance	f = 1.0 MHz		N-Ch		185		pF
				P-Ch		245		

Symbol	Parameter	Conditions	Type	Min	Тур	Max	Units
SWITCHII	NG CHARACTERISTICS (Note 2)		'				
t _{D(on)}	Turn - On Delay Time	N-Channel	N-Ch		6	10	ns
		$V_{DD} = 10 \text{ V}, I_{D} = 1 \text{ A},$	P-Ch		9	40	
r	Turn - On Rise Time	V_{GEN} = 10 V, R_{GEN} = 6 Ω	N-Ch		12	25	ns
		P-Channel	P-Ch		17	25	
D(off)	Tum - Off Delay Time	$V_{DD} = -10 \text{ V}, \ I_{D} = -1 \text{ A}, \ V_{GEN} = -10 \text{ V}, \ R_{GEN} = 6 \Omega$	N-Ch		22	30	ns
		V _{GEN} = -10 V, 1\(\text{GEN} = 0.22\)	P-Ch		26	30	
Turn - Off Fall Time	Turn - Off Fall Time		N-Ch		8	20	ns
			P-Ch		13	20	
J [®]	Total Gate Charge	N-Channel	N-Ch		17	30	nC nC
		$V_{DS} = 10 \text{ V},$ $I_{D} = 3.5 \text{ A}, V_{GS} = 10 \text{ V}$	P-Ch		19	30	
Q_{gs}	Gate-Source Charge	I _D = 3.5 A, V _{GS} = 10 V	N-Ch		1.2	6	
		P-Channel V _{DS} = -10 V,	P-Ch		3	6	
Q_{gd}	Gate-Drain Charge	$I_{D} = -3.5 \text{ A}, V_{GS} = -10 \text{ V}$	N-Ch		5	12	nC
			P-Ch		9	12	
DRAIN-SC	OURCE DIODE CHARACTERISTIC	CS AND MAXIMUM RATINGS					
s	Maximum Continuous Drain-Sour	ce Diode Forward Current	N-Ch			1.7	Α
			P-Ch			-1.7	
V _{SD}	Drain-Source Diode Forward	V _{GS} = 0 V, I _S = 1.7 A (Note 2)	N-Ch		0.86	1.2	V
	Voltage	V _{GS} = 0 V, I _S = -1.7 A (Note 2)	P-Ch		-0.9	-1.2	
r	Reverse Recovery Time	$V_{GS} = 0V$, $I_F = 3.5$ A, $dI_F / dt = 100$ A/ μ s	N-Ch			100	ns
"			P-Ch			100	1

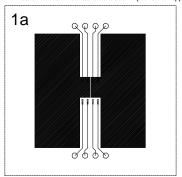
Notes:

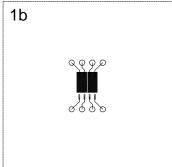
1. $R_{g,x}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{g,c}$ is guaranteed by design while $R_{g,c}$ is determined by the user's board design.

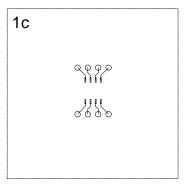
$$P_D(t) = \frac{T_{J} - T_A}{R_{\theta J} A(t)} = \frac{T_{J} - T_A}{R_{\theta J} d_t R_{\theta C} A(t)} = I_D^2(t) \times R_{DS(ON)} \hat{\mathbf{Q}}_{T_J}$$

Typical R_{BJA} for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 78°C/W when mounted on a 0.5 in² pad of 2oz cpper.
- b. 125°C/W when mounted on a 0.02 in² pad of 2oz cpper.
- c. 135°C/W when mounted on a 0.003 in² pad of 2oz cpper.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2.0%.

Typical Electrical Characteristics: N-Channel

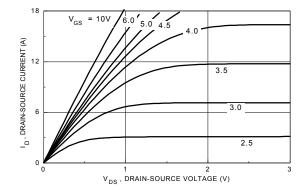


Figure 1. On-Region Characteristics.

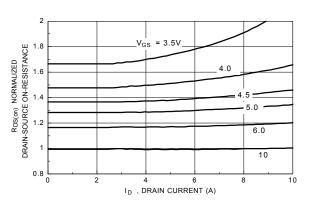


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current.

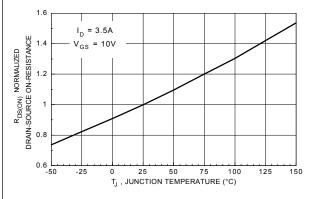


Figure 3. On-Resistance Variation with Temperature.

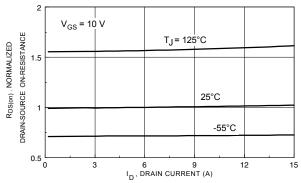


Figure 4. On-Resistance Variation with Drain Current and Temperature.

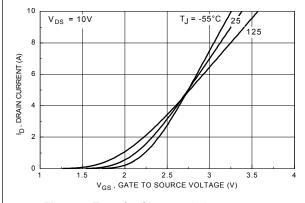


Figure 5. Transfer Characteristics.

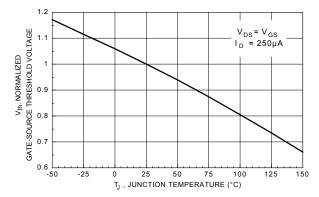


Figure 6. Gate Threshold Variation with Temperature.

Typical Electrical Characteristics: N-Channel (continued)

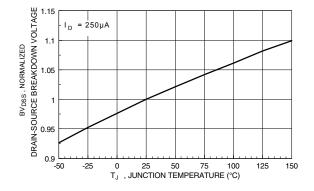


Figure 7. Breakdown Voltage Variation with Temperature.

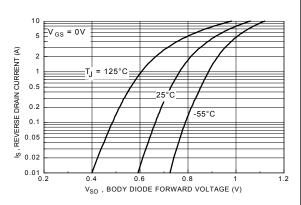


Figure 8. Body Diode Forward Voltage Variation with Current and Temperature

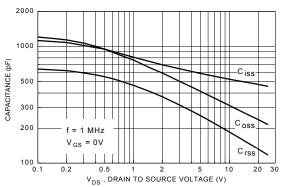


Figure 9. Capacitance Characteristics.

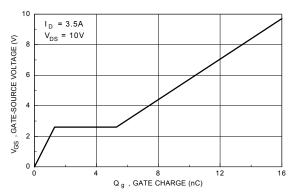


Figure 10. Gate Charge Characteristics.

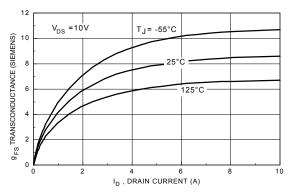


Figure 11. Transconductance Variation with Drain Current and Temperature.

Typical Electrical Characteristics: P-Channel

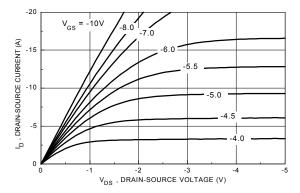


Figure 12. On-Region Characteristics.

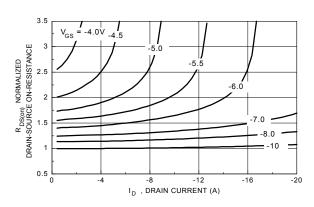


Figure 13. On-Resistance Variation with Gate Voltage and Drain Current.

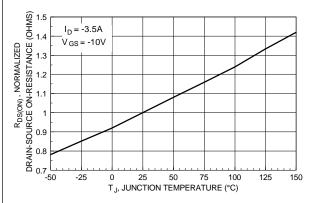


Figure 14. On-Resistance Variation with Temperature.

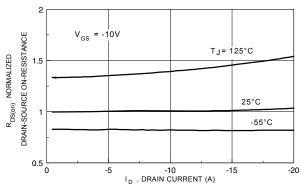


Figure 15. On-Resistance Variation with Drain Current and Temperature.

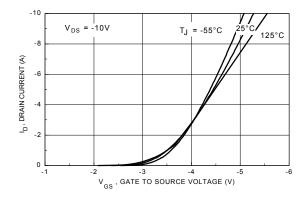


Figure 16. Drain Current Variation with Gate Voltage and Temperature.

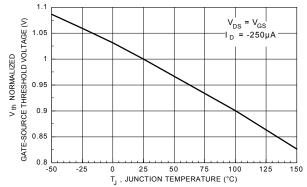


Figure 17. Gate Threshold Variation with Temperature.

Typical Electrical Characteristics: P-Channel (continued)

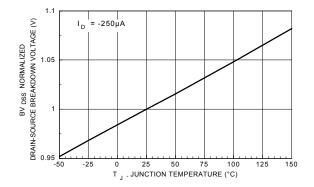


Figure 18. Breakdown Voltage Variation with Temperature.

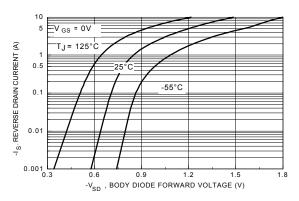


Figure 19. Body Diode Forward Voltage
Variation with Current and Temperature

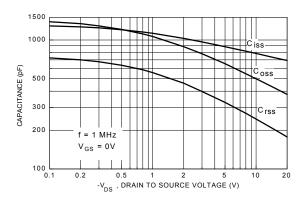


Figure 20. Capacitance Characteristics.

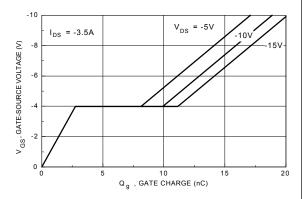


Figure 21. Gate Charge Characteristics

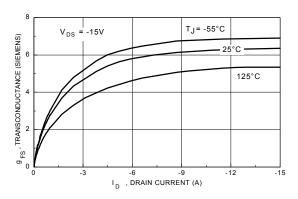


Figure 22. Transconductance Variation with Drain Current and Temperature.

Typical Electrical Characteristic: N & P-Channel (continued)

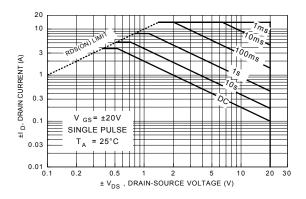


Figure 23. Maximum Safe Operating Area.

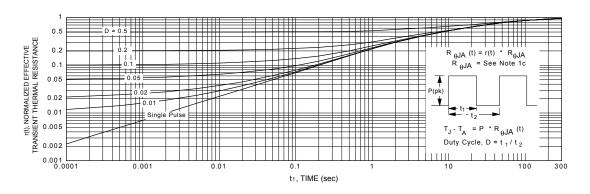
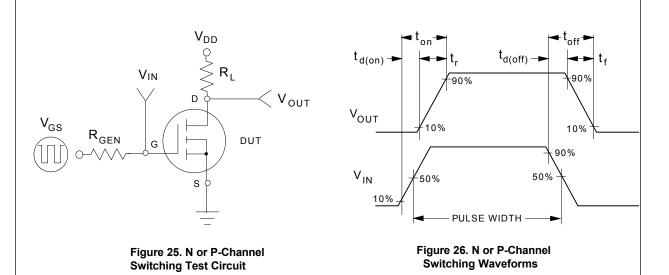


Figure 24. Transient Thermal Response Curve.

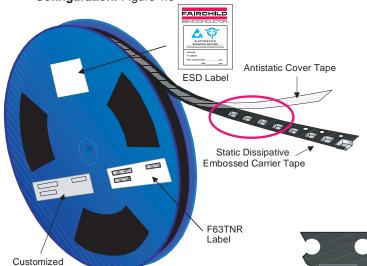
Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.



SO-8 Tape and Reel Data and Package Dimensions





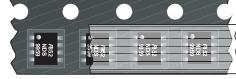


Packaging Description:

Packaging Description:

SOIC-8 parts are shipped in tape. The carrier tape is made from a dissipative (carbon filled) polycarbonate resin. The cover tape is a multilayer film (Heat Activated Adhesive in nature) primarily composed of polyester film, adhesive layer, sealant, and amit-static sprayed agent. These reeled parts in standard option are shipped with 2,500 units per 13° or 300cm diameter reel. The reels are dark blue in color and is made of polystyrene plastic (antistatic coated). Other option comes in 500 units per 7° or 177cm diameter reel. This and some other options are further described in the Packaging Information table.

These full reles are individually barcode labeled and placed inside a standard intermediate box (illustrated in figure 1.0) made of recyclable corrugated brown paper. One box contains two reels maximum. And these boxes are placed inside a barcode labeled shipping box which comes in different sizes depending on the number of parts shipped.





S	SOIC (8lds) Packaging Information									
Packaging Option	Standard (no flow code)	L86Z	F011	D84Z						
Packaging type	TNR	Rail/Tube	TNR	TNR						
Qty per Reel/Tube/Bag	2,500	95	4,000	500						
Reel Size	13" Dia	-	13" Dia	7" Dia						
Box Dimension (mm)	343x64x343	530x130x83	343x64x343	184x187x47						
Max qty per Box	5,000	30,000	8,000	1,000						
Weight per unit (gm)	0.0774	0.0774	0.0774	0.0774						
Weight per Reel (kg)	0.6060	-	0.9696	0.1182						
Note/Comments										

SOIC-8 Unit Orientation

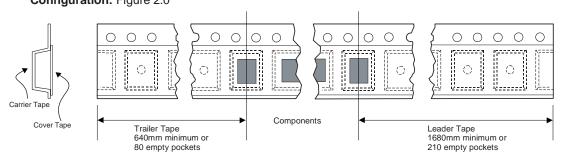


Label



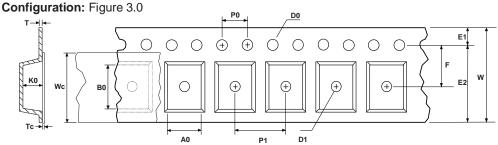
343mm x 342mm x 64mm Standard Intermediate box ESD Label F63TNLabel F63TN Label

SOIC(8lds) Tape Leader and Trailer Configuration: Figure 2.0





SOIC(8lds) Embossed Carrier Tape



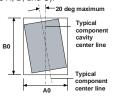


	Dimensions are in millimeter													
Pkg type	Α0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
SOIC(8lds) (12mm)	6.50 +/-0.10	5.30 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.60 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	2.1 +/-0.10	0.450 +/- 0.150	9.2 +/-0.3	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).

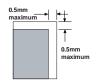


Sketch A (Side or Front Sectional View)
Component Rotation



Sketch B (Top View)

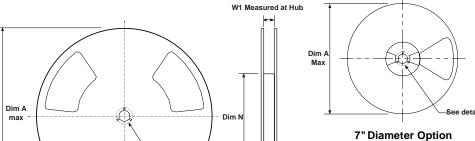
Component Rotation



Sketch C (Top View)

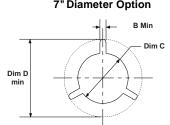
Component lateral movement

SOIC(8lds) Reel Configuration: Figure 4.0



See detail AA W3

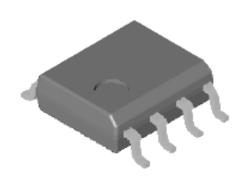
13" Diameter Option W2 max Measured at Hub

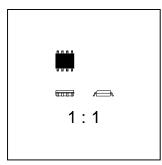


								DETAIL AA	
	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	2.165 55	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

SO-8 Tape and Reel Data and Package Dimensions, continued

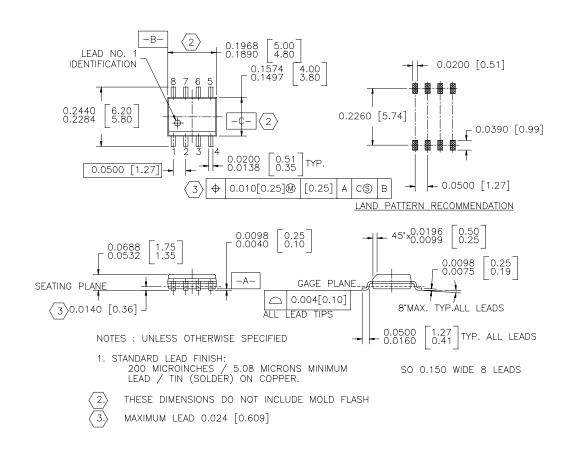
SOIC-8 (FS PKG Code S1)





Scale 1:1 on letter size paper
Dimensions shown below are in:
inches [millimeters]

Part Weight per unit (gram): 0.0774



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FAST® Quiet Series $^{\text{TM}}$ SuperSOT $^{\text{TM}}$ -3 SuperSOT $^{\text{TM}}$ -6

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition					
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.					
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.					
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.					
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.					